

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
212740US-2SRD CONTSERIAL NO.
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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yoshiyuki MATSUNAGA, et al.

FILING DATE

Herewith

GROUP

Unassigned

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| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
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Examiner

AUNG S. MOE

Date Considered

2/7/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.